

XXXIX PANDA Collaboration Meeting 12-16 December 2011

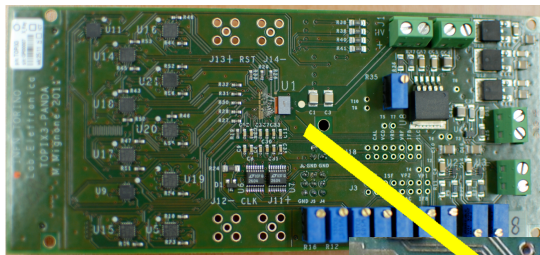
Pixel Test

Laura Zotti

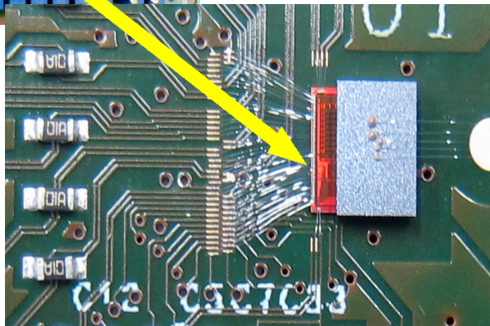
Università degli Studi di Torino & INFN-Torino



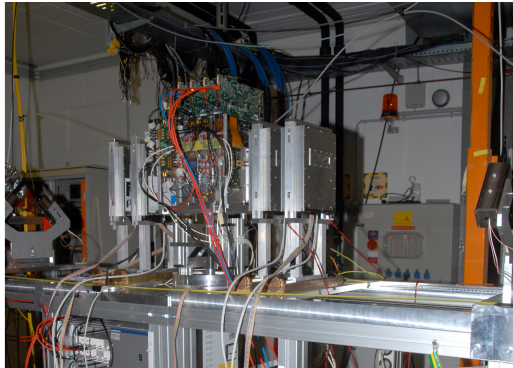
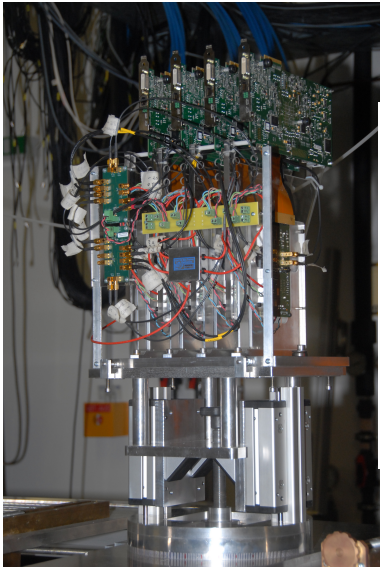
Jülich Beam Test November 28th - December 3th



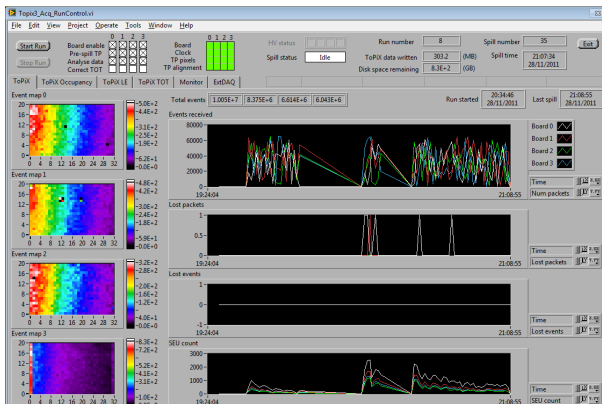
4 Boards
equipped with
640 pixel cells



Jülich Beam Test November 28th - December 3th



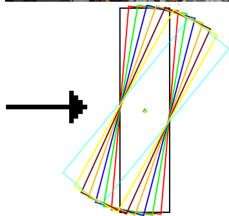
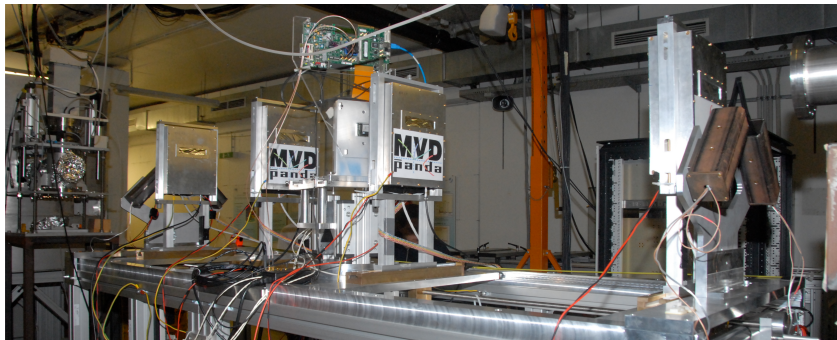
Jülich Beam Test November 28th - December 3th



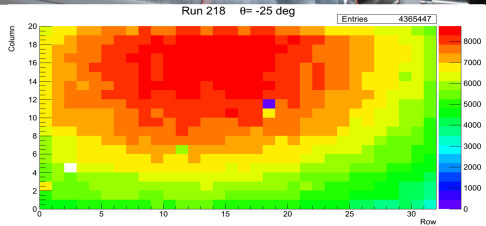
233 Runs ~ 130 GB of data

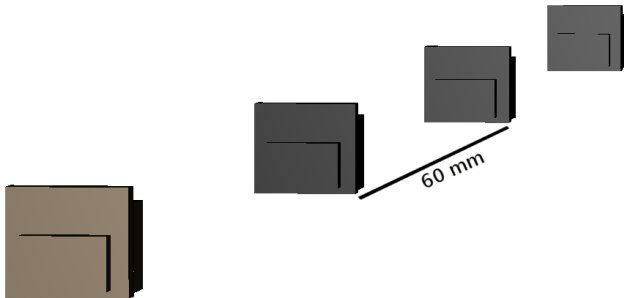
- HV sensors scan (from 10 V up to 50 V)
- TOT threshold scan (from 695 mV up to 650 mV)
- 1 board rotation

Jülich Beam Test November 28th - December 3th



θ [deg]
5
10
15
20
25
30
40





Geometry Description

- Passive Silicon
- Active Silicon
- ToPix
- Board Layers (Cu+FR4)
- Capacitor

PixelHit

- Int_t Box
- Int_t Col
- Int_t Row
- Double_t Charge
- Long64_t Timestamp
- Int_t Spill

